

# DIM600DDS12-A000

## **Dual Switch IGBT Module**

Replaces DS5868-2

DS5868-3 July 2014 (LN31761)

### **FEATURES**

- 10µs Short Circuit Withstand
- Non Punch Through Silicon
- Isolated Cu Base with Al<sub>2</sub>O<sub>3</sub> Substrates
- Lead Free construction

## **APPLICATIONS**

- High Reliability Inverters
- Motor Controllers

The Powerline range of high power modules includes half bridge, chopper, dual, single and bi-directional switch configurations covering voltages from 600V to 3300V and currents up to 2400A.

The DIM600DDS12-A000 is a dual switch 1200V, n-channel enhancement mode, insulated gate bipolar transistor (IGBT) module. The IGBT has a wide reverse bias safe operating area (RBSOA) plus 10µs short circuit withstand. This device is optimised for traction drives and other applications requiring high thermal cycling capability.

The module incorporates an electrically isolated base plate and low inductance construction enabling circuit designers to optimise circuit layouts and utilise grounded heat sinks for safety.

#### ORDERING INFORMATION

Order As:

## DIM600DDS12-A000

Note: When ordering, please use the complete part number

#### **KEY PARAMETERS**

| $V_{CES}$            |         | 1200V |
|----------------------|---------|-------|
| V <sub>CE(sat)</sub> | * (typ) | 2.2 V |
| l <sub>c</sub> ` ´   | (max)   | 600A  |
| I <sub>C(PK)</sub>   | (max)   | 1200A |

<sup>\*</sup> Measured at the power busbars, not the auxiliary terminals

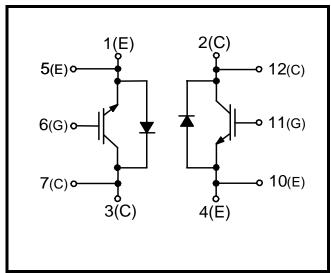


Fig. 1 Circuit configuration

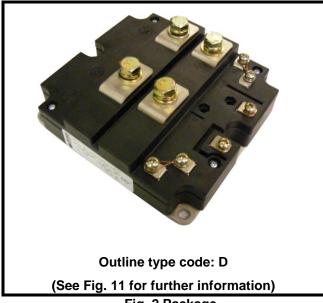


Fig. 2 Package



## **ABSOLUTE MAXIMUM RATINGS**

Stresses above those listed under 'Absolute Maximum Ratings' may cause permanent damage to the device. In extreme conditions, as with all semiconductors, this may include potentially hazardous rupture of the package. Appropriate safety precautions should always be followed. Exposure to Absolute Maximum Ratings may affect device reliability.

T<sub>case</sub> = 25°C unless stated otherwise

| Symbol             | Parameter                         | Test Conditions  | Max. | Units             |
|--------------------|-----------------------------------|--|------|-------------------|
| V <sub>CES</sub>   | Collector-emitter voltage         | V <sub>GE</sub> = 0V                                     | 1200 | V                 |
| $V_{GES}$          | Gate-emitter voltage              |  | ±20  | V                 |
| I <sub>C</sub>     | Continuous collector current      | T <sub>case</sub> = 85°C                                 | 600  | Α                 |
| I <sub>C(PK)</sub> | Peak collector current            | 1ms, T <sub>case</sub> = 115°C                           | 1200 | Α                 |
| P <sub>max</sub>   | Max. transistor power dissipation | $T_{case} = 25^{\circ}C, T_{j} = 150^{\circ}C$           | 5208 | W                 |
| l <sup>2</sup> t   | Diode I <sup>2</sup> t value      | $V_R = 0$ , $t_p = 10$ ms, $T_j = 125$ °C                | 100  | kA <sup>2</sup> s |
| V <sub>isol</sub>  | Isolation voltage – per module    | Commoned terminals to base plate.<br>AC RMS, 1 min, 50Hz | 2500 | V                 |

#### THERMAL AND MECHANICAL RATINGS

| Symbol               | Parameter  | Test Conditions                            | Min | Тур. | Max | Units |
|----------------------|--|--|-----|------|-----|-------|
| R <sub>th(j-c)</sub> | Thermal resistance – transistor (per switch)       | Continuous dissipation - junction to case  | -   | -    | 24  | °C/kW |
| R <sub>th(j-c)</sub> | Thermal resistance – diode (per switch)            | Continuous dissipation - junction to case  | -   | -    | 40  | °C/kW |
| R <sub>th(c-h)</sub> | Thermal resistance – case to heatsink (per module) | Mounting torque 5Nm (with mounting grease) | -   | -    | 8   | °C/kW |
| T <sub>j</sub>       | Junction temperature                               | Transistor                                 | -   | -    | 150 | °C    |
|                      |  | Diode                                      | -   | -    | 125 | °C    |
| T <sub>stg</sub>     | Storage temperature range                          | -  | -40 | -    | 125 | °C    |
|                      |  | Mounting – M6                              | -   | -    | 5   | Nm    |
|                      | Screw torque                                       | Electrical connections – M4                | -   | -    | 2   | Nm    |
|                      |  | Electrical connections – M8                | -   | -    | 10  | Nm    |



## **ELECTRICAL CHARACTERISTICS**

 $T_{case}$  = 25°C unless stated otherwise.

| Symbol               | Parameter                                   | Test Conditions  | Min | Тур  | Max  | Units |
|----------------------|---|--|-----|------|------|-------|
|                      | Collector cut-off current                   | $V_{GE} = 0V$ , $V_{CE} = V_{CES}$   |     |      | 1    | mA    |
| I <sub>CES</sub>     |   | $V_{GE} = 0V$ , $V_{CE} = V_{CES}$ , $T_{case} = 125$ °C   |     |      | 18   | mA    |
| I <sub>GES</sub>     | Gate leakage current                        | $V_{GE} = \pm 20V, V_{CE} = 0V$  |     |      | 3    | μΑ    |
| V <sub>GE(TH)</sub>  | Gate threshold voltage                      | $I_C = 20$ mA, $V_{GE} = V_{CE}$   | 4.5 | 5.5  | 6.5  | V     |
|                      | Collector-emitter saturation voltage        | V <sub>GE</sub> = 15V, I <sub>C</sub> = 400A   |     | 2.2  | 2.8  | V     |
| V <sub>CE(sat)</sub> |   | V <sub>GE</sub> = 15V, I <sub>C</sub> = 400A, T <sub>j</sub> = 125°C   |     | 2.6  | 3.2  | V     |
| I <sub>F</sub>       | Diode forward current                       | DC   |     |      | 600  | Α     |
| I <sub>FM</sub>      | Diode maximum forward current               | t <sub>p</sub> = 1ms   |     |      | 1200 | Α     |
|                      | Diode forward voltage                       | I <sub>F</sub> = 400A  |     | 2.1  | 2.4  | V     |
| $V_{F}$              |   | I <sub>F</sub> = 400A, T <sub>j</sub> = 125°C  |     | 2.1  | 2.4  | V     |
| C <sub>ies</sub>     | Input capacitance                           | $V_{CE} = 25V, V_{GE} = 0V, f = 1MHz$  |     | 70   |      | nF    |
| Qg                   | Gate charge                                 | ±15V   |     | 6    |      | μC    |
| C <sub>res</sub>     | Reverse transfer capacitance                | $V_{CE} = 25V, V_{GE} = 0V, f = 1MHz$  |     |      |      | nF    |
| L <sub>M</sub>       | Module inductance – per switch              |  |     | 20   |      | nΗ    |
| R <sub>INT</sub>     | Internal transistor resistance – per switch |  |     | 270  |      | μΩ    |
| SC <sub>Data</sub>   | Short circuit current, I <sub>SC</sub>      | $T_{j} = 125^{\circ}\text{C}, V_{CC} = 900\text{V}$ $t_{p} \le 10\mu\text{s}, V_{GE} \le 15\text{V}$ $V_{CE \text{ (max)}} = V_{CES} - L^{*}x \text{ dI/dt}$ IEC 60747-9 |     | 3400 |      | А     |

## Note:

L is the circuit inductance + L<sub>M</sub>



## **ELECTRICAL CHARACTERISTICS**

T<sub>case</sub> = 25°C unless stated otherwise

| Symbol              | Parameter                      | Test Conditions   | Min | Тур. | Max | Units |
|---------------------|--------------------------------|---|-----|------|-----|-------|
| t <sub>d(off)</sub> | Turn-off delay time            | $I_{C} = 600A$ $V_{GF} = \pm 15V$   |     | 920  |     | ns    |
| t <sub>f</sub>      | Fall time                      |   |     | 140  |     | ns    |
| E <sub>OFF</sub>    | Turn-off energy loss           | $V_{GE} = £13V$ $V_{CE} = 600V$   |     | 100  |     | mJ    |
| t <sub>d(on)</sub>  | Turn-on delay time             | $R_{G(ON)} = 2.7\Omega$ $R_{G(OFF)} = 2.7\Omega$ $L_{S} \sim 120 \text{nH}$ |     | 390  |     | ns    |
| t <sub>r</sub>      | Rise time                      |   |     | 180  |     | ns    |
| E <sub>ON</sub>     | Turn-on energy loss            |   |     | 55   |     | mJ    |
| $Q_{rr}$            | Diode reverse recovery charge  | $I_F = 600A$ $V_{CE} = 600V$ $dI_F/dt = 3600A/\mu s$                        |     | 100  |     | μC    |
| I <sub>rr</sub>     | Diode reverse recovery current |   |     | 370  |     | Α     |
| E <sub>rec</sub>    | Diode reverse recovery energy  |   |     | 50   |     | mJ    |

## $T_{case}$ = 125°C unless stated otherwise

| Symbol              | Parameter                      | Test Conditions   | Min | Тур. | Max | Units |
|---------------------|--------------------------------|---|-----|------|-----|-------|
| t <sub>d(off)</sub> | Turn-off delay time            |   |     | 1000 |     | ns    |
| t <sub>f</sub>      | Fall time                      | $I_C = 600A$ $V_{GF} = \pm 15V$   |     | 160  |     | ns    |
| E <sub>OFF</sub>    | Turn-off energy loss           | $V_{CE} = 600V$   |     | 125  |     | mJ    |
| t <sub>d(on)</sub>  | Turn-on delay time             | $R_{G(ON)} = 2.7\Omega$ $R_{G(OFF)} = 2.7\Omega$ $L_S \sim 120 \text{nH}$ |     | 460  |     | ns    |
| t <sub>r</sub>      | Rise time                      |   |     | 180  |     | ns    |
| E <sub>ON</sub>     | Turn-on energy loss            |   |     | 65   |     | mJ    |
| $Q_{rr}$            | Diode reverse recovery charge  | $I_F = 600A$ $V_{CE} = 600V$ $dI_F/dt = 3600A/\mu s$                      |     | 200  |     | μC    |
| I <sub>rr</sub>     | Diode reverse recovery current |   |     | 480  |     | Α     |
| E <sub>rec</sub>    | Diode reverse recovery energy  |   |     | 100  |     | mJ    |



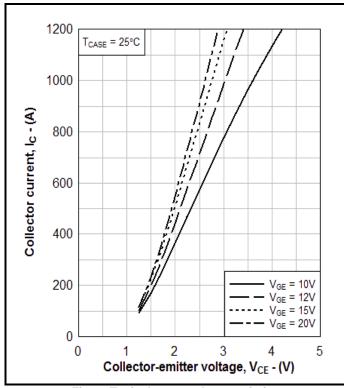


Fig. 3 Typical output characteristics

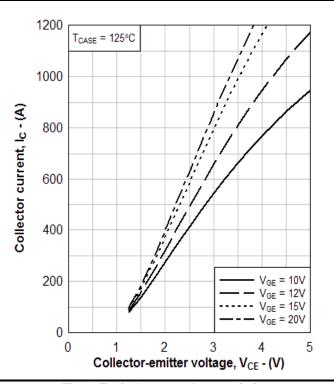


Fig. 4 Typical output characteristics

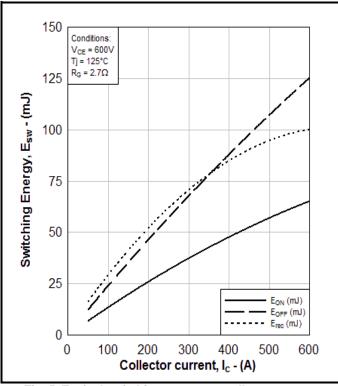


Fig. 5 Typical switching energy vs collector current

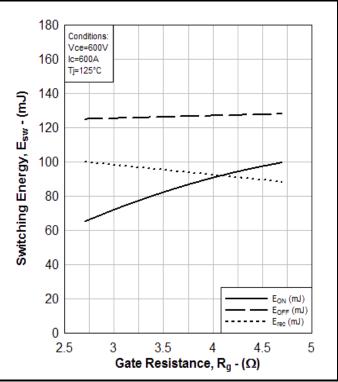


Fig. 6 Typical switching energy vs gate resistance



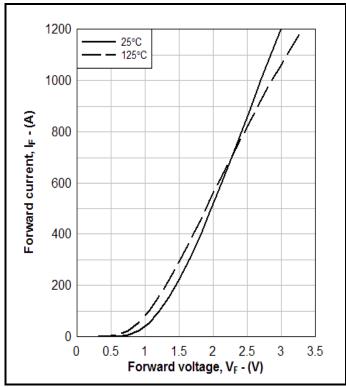


Fig. 7 Diode typical forward characteristics

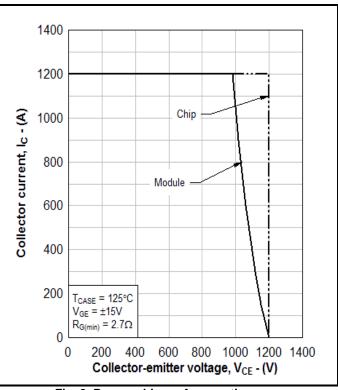


Fig. 8 Reverse bias safe operating area

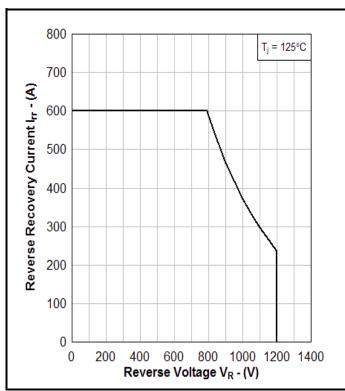


Fig. 9 Diode reverse bias safe operating area

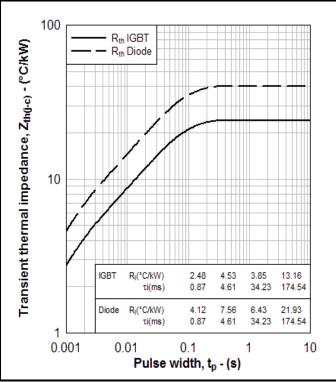


Fig. 10 Transient thermal impedance



## **PACKAGE DETAILS**

For further package information, please visit our website or contact Customer Services. All dimensions in mm, unless stated otherwise.

## DO NOT SCALE.

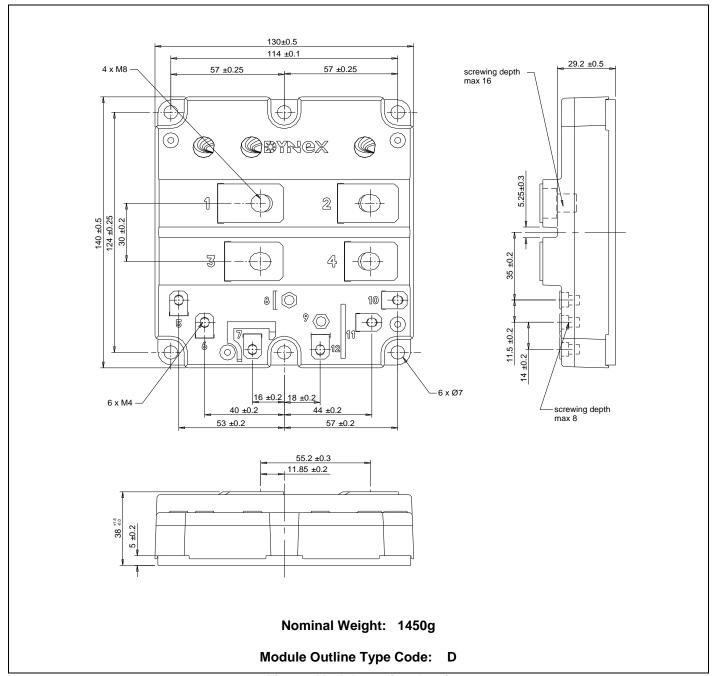


Fig. 11 Module outline drawing



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